1. General description

The 74ABT125 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT125 device is a quad buffer that is ideal for driving bus lines. The device features four output enable inputs $(1\overline{OE}, 2\overline{OE}, 3\overline{OE}, 4\overline{OE})$, each controlling one of the 3-state outputs.

2. Features and benefits

- Quad bus interface
- 3-state buffers
- Live insertion and extraction permitted
- Output capability: HIGH –32 mA; LOW +64 mA
- Power-up 3-state
- Inputs are disabled during 3-state mode
- Latch-up protection exceeds 500 mA per JESD78 class II level A
- ESD protection:
 - HBM JESD22-A114F exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from –40 °C to +85 °C

3. Ordering information

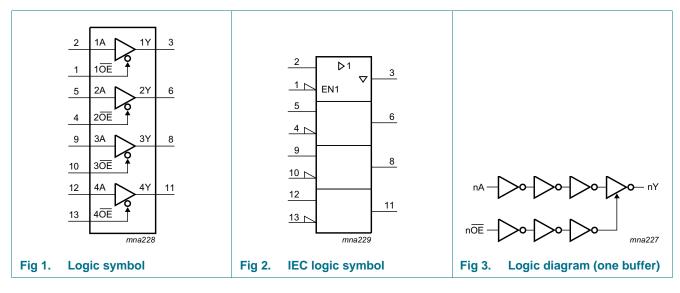
Table 1.Ordering information

Type number	Package								
	Temperature range	Name	Description	Version					
74ABT125D	–40 °C to +85 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1					
74ABT125DB	–40 °C to +85 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1					
74ABT125PW	–40 °C to +85 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1					
74ABT125BQ	−40 °C to +85 °C	DHVQFN14	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body $2.5 \times 3 \times 0.85$ mm	SOT762-1					



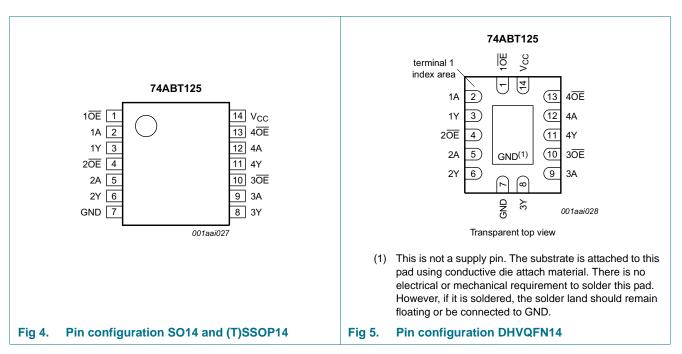
Quad buffer; 3-state

4. Functional diagram



5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description						
Symbol	Pin	Description				
1OE to 4OE	1, 4, 10, 13	output enable input (active LOW)				
1A to 4A	2, 5, 9, 12	data input				
1Y to 4Y	3, 6, 8, 11	data output				
GND	7	ground (0 V)				
V _{CC}	14	supply voltage				

6. Functional description

Table 3. Function selection^[1]

Inputs nOE	Output	
nOE	nA	nY
L	L	L
L	Н	Н
Н	X	Z

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

7. Limiting values

Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{CC}	supply voltage			-0.5	+7.0	V
VI	input voltage			-1.2	+7.0	V
Vo	output voltage	output in OFF-state or HIGH-state		-0.5	+5.5	V
I _{IK}	input clamping current	V ₁ < 0 V		-18	-	mA
I _{ОК}	output clamping current	V _O < 0 V		-50	-	mA
lo	output current	output in LOW-state		-	128	mA
Tj	junction temperature		<u>[2]</u>	-	150	°C
T _{stg}	storage temperature			-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 \text{ °C to } +85 \text{ °C}$	<u>[3]</u>	-	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

[3] SO14 packages: above 70 °C P_{tot} derate linearly with 8 mW/K
 SSOP14 and TSSOP14 packages: above 60 °C P_{tot} derate linearly with 5.5 mW/K
 DHVQFN14 packages: above 60 °C P_{tot} derate linearly with 4.5 mW/K

8. Recommended operating conditions

Table 5.Operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		4.5	5.5	V
VI	input voltage		0	V _{CC}	V
V _{IH}	HIGH-level input voltage		2.0	-	V
V _{IL}	LOW-level Input voltage		-	0.8	V
I _{OH}	HIGH-level output current		-32	-	mA
I _{OL}	LOW-level output current		-	64	mA
$\Delta t / \Delta V$	input transition rise and fall rate		-	10	ns/V
T _{amb}	ambient temperature	in free air	-40	+85	°C

9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions			25 °C		–40 °C t	Unit	
				Min	Тур	Max	Min	Min Max	
V _{IK}	input clamping voltage	V_{CC} = 4.5 V; I _{IK} = -18 mA		-	-0.9	-1.2	-	-1.2	V
V _{OH}	HIGH-level output	$V_{I} = V_{IL} \text{ or } V_{IH}$							
	voltage	V_{CC} = 4.5 V; I _{OH} = -3 mA		2.5	2.9	-	2.5	-	V
		$V_{CC} = 5.0 \text{ V}; \text{ I}_{OH} = -3 \text{ mA}$		3.0	3.4	-	3.0	-	V
		V_{CC} = 4.5 V; I _{OH} = -32 mA		2.0	2.4	-	2.0	-	V
V _{OL}	LOW-level output voltage	$\label{eq:V_CC} \begin{array}{l} V_{CC} = 4.5 \; V; \; I_{OL} = 64 \; mA; \\ V_{I} = V_{IL} \; or \; V_{IH} \end{array}$			0.35	0.55	-	0.55	V
li	input leakage current	V_{CC} = 5.5 V; V_{I} = GND or 5.5 V	V _{CC} = 5.5 V; V _I = GND or 5.5 V		±0.01	±1.0	-	±1.0	μΑ
OFF	power-off leakage current	V_{CC} = 0.0 V; V_{I} or $V_{O} \leq 4.5$ V		-	±5.0	±100	-	±100	μΑ
I _{O(pu/pd)}	power-up/power-down output current	V_{CC} = 2.1 V; V_O = 0.5 V; V _I = GND or V _{CC} ; \overline{OE} = don't care	<u>[1]</u>	-	±5.0	±50	-	±50	μΑ
loz	OFF-state output	V_{CC} = 5.5 V; V_I = V_{IL} or V_{IH}							
	current	V _O = 2.7 V		-	1.0	50	-	50	μA
		V _O = 0.5 V		-	-1.0	-50	-	-50	μA
I _{CEX}	output high leakage current	HIGH-state; $V_0 = 5.5 V$; $V_{CC} = 5.5 V$; $V_I = GND \text{ or } V_{CC}$		-	5.0	50	-	50	μΑ
lo	output current	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	[2]	-50	-100	-180	-50	-180	mA
lcc	supply current	V_{CC} = 5.5 V; V_I = GND or V_{CC}							
		outputs HIGH-state		-	65	250	-	250	μΑ
		outputs LOW-state		-	12	15	-	30	mA
		outputs disabled		-	65	250	-	50	μA

Table 6.	able 6. Static characteristics continued								
Symbol	Parameter	Conditions			25 °C		–40 °C t	o +85 °C	Unit
				Min	Тур	Max	Min	Max	
Δl _{CC}	additional supply current	per control pin; $V_{CC} = 5.5 V$; one control input at 3.4 V, other inputs at V_{CC} or GND	[3]						
		outputs enabled		-	0.5	1.5	-	1.5	mA
		outputs disabled		-	50	250	-	250	mA
		one enable input at 3.4 V and other inputs at V_{CC} or GND; outputs disabled		-	0.5	1.5	-	1.5	mA
CI	input capacitance	$V_{I} = 0 V \text{ or } V_{CC}$		-	4	-	-	-	pF
Co	output capacitance	outputs disabled; $V_0 = 0 V \text{ or } V_{CC}$		-	7	-	-	-	pF

Ta

This parameter is valid for any V_{CC} between 0 V and 2.1 V, with a transition time of up to 10 ms. From V_{CC} = 2.1 V to V_{CC} = 5 V \pm 10 %, [1] a transition time of up to 100 μ s is permitted.

Not more than one output should be tested at a time, and the duration of the test should not exceed one second. [2]

[3] This is the increase in supply current for each input at 3.4 V.

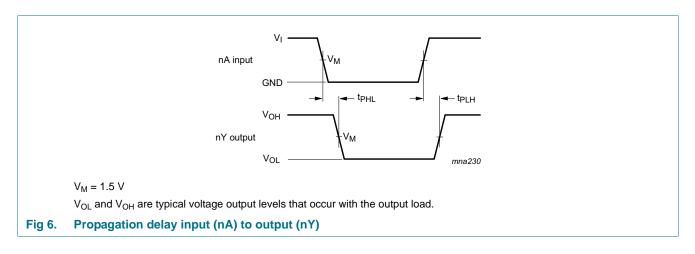
10. Dynamic characteristics

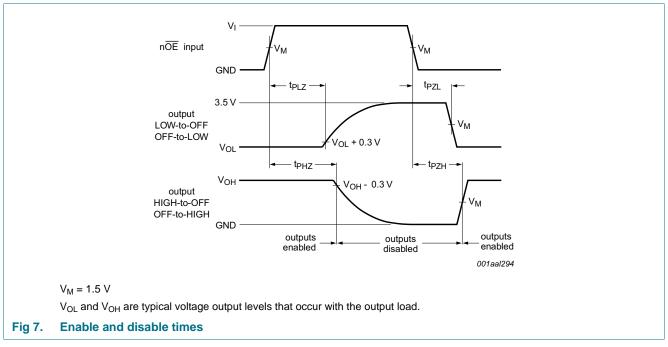
Table 7. **Dynamic characteristics**

GND = 0 V. Test circuit is shown in Figure 8.

Symbol	Parameter	Conditions	25 °C; V _{CC} = 5.0 V			–40 °C to V _{CC} = 5.0	Unit	
			Min	Тур	Max	Min	Max	
t _{PLH}	LOW to HIGH propagation delay	nA to nY, see Figure 6	1.0	2.8	4.1	1.0	4.6	ns
t _{PHL}	HIGH to LOW propagation delay	nA to nY; see Figure 6	1.0	3.1	4.6	1.0	4.9	ns
t _{PZH}	OFF-state to HIGH propagation delay	$n\overline{OE}$ to nY; see <u>Figure 7</u>	1.0	3.2	5.0	1.0	5.9	ns
t _{PZL}	OFF-state to LOW propagation delay	nOE to nY; see <u>Figure 7</u>	1.0	4.2	6.2	1.0	6.8	ns
t _{PHZ}	HIGH to OFF-state propagation delay	$n\overline{OE}$ to nY; see <u>Figure 7</u>	1.0	4.1	5.4	1.0	6.2	ns
t _{PLZ}	LOW to OFF-state propagation delay	$n\overline{OE}$ to nY; see Figure 7	1.5	2.8	5.0	1.5	5.5	ns

11. Waveforms





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Quad buffer; 3-state

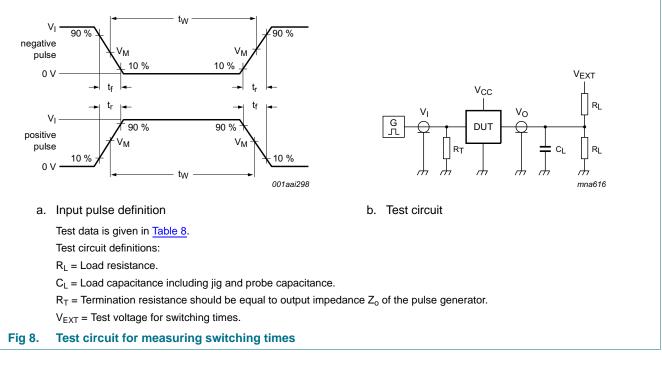


Table 8. Test data

Input			Load		V _{EXT}			
VI	fı	tw	t _r , t _f	CL	RL	t _{PHL} , t _{PLH}	t _{PZH} , t _{PHZ}	t _{PZL} , t _{PLZ}
3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500 Ω	open	open	7.0 V

Quad buffer; 3-state

12. Package outline

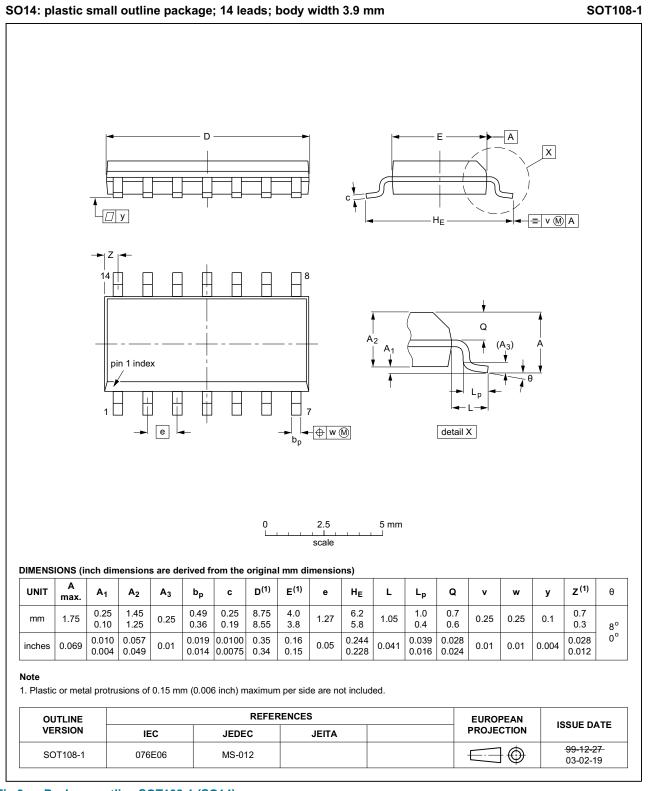
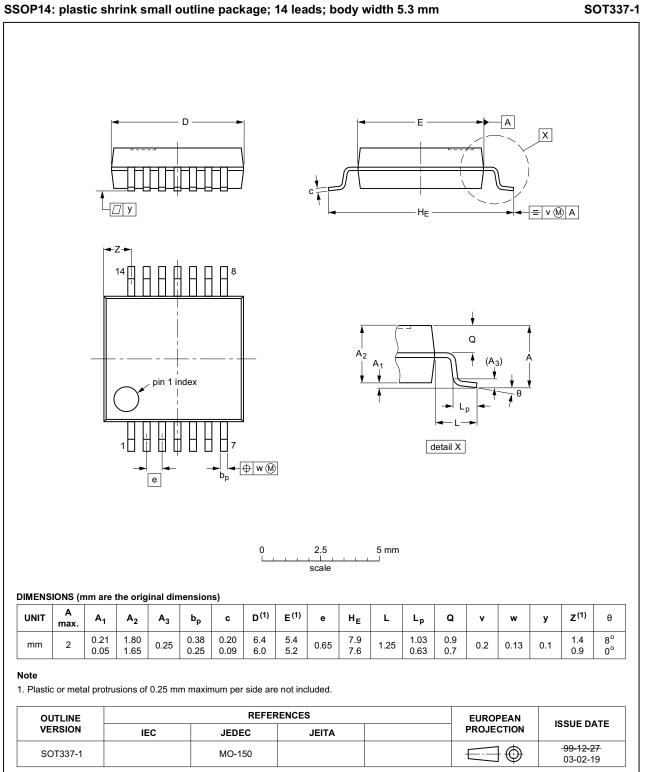


Fig 9. Package outline SOT108-1 (SO14)

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SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

Fig 10. Package outline SOT337-1 (SSOP14)

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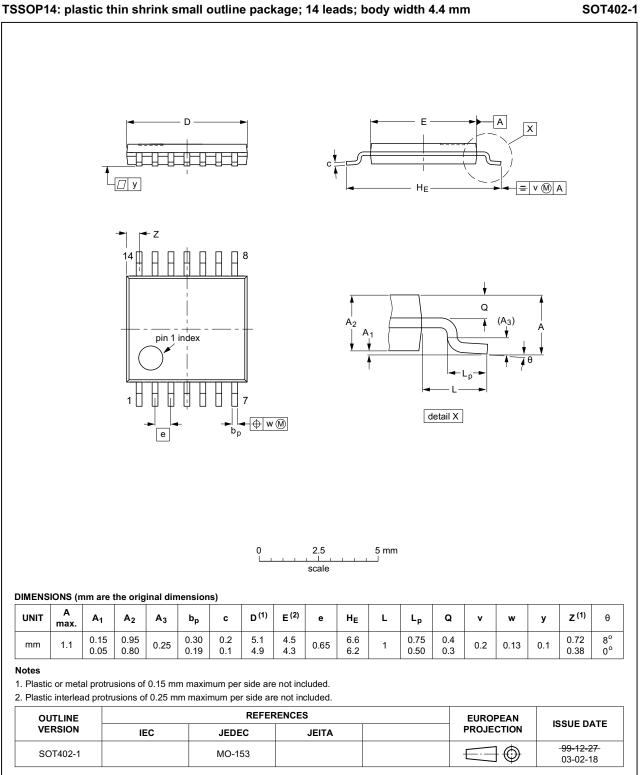
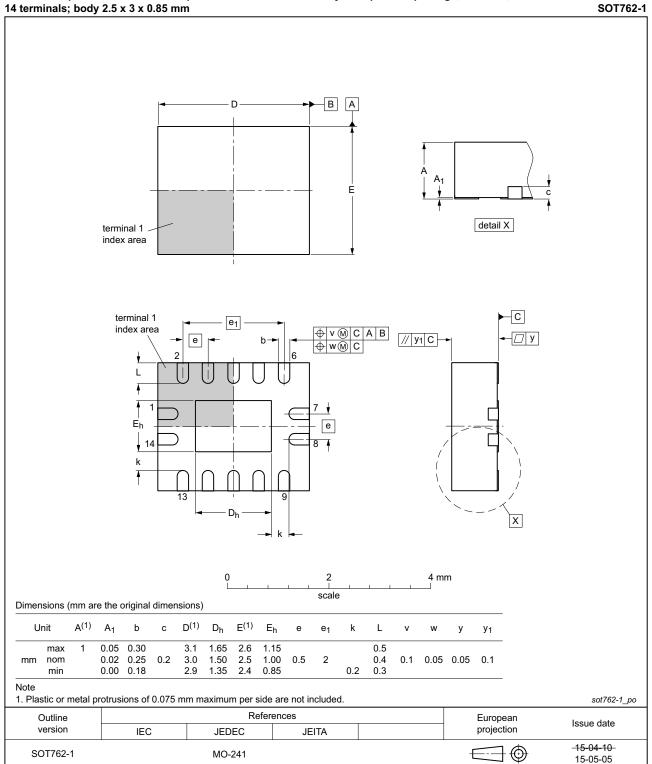


Fig 11. Package outline SOT402-1 (TSSOP14)

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DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm

Fig 12. Package outline SOT762-1 (DHVQFN14)

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Quad buffer; 3-state

13. Abbreviations

Table 9. Abbreviations						
Acronym	Description					
BiCMOS	BipolarCMOS					
DUT	Device Under Test					
ESD	ElectroStatic Discharge					
HBM	Human Body Model					
MM	Machine Model					

14. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ABT125 v.7	20151125	Product data sheet	-	74ABT125 v.6
Modifications:	 Type numb 	oer 74ABT125N (SOT27-1) re	emoved.	
74ABT125 v.6	20111103	Product data sheet	-	74ABT125 v.5
Modifications:	 Legal page 	s updated		
74ABT125 v.5	20101124	Product data sheet	-	74ABT125 v.4
74ABT125 v.4	20100427	Product data sheet	-	74ABT125 v.3
74ABT125 v.3	20080429	Product data sheet	-	74ABT125 v.2
74ABT125 v.2	19980116	Product specification	-	74ABT125 v.1
74ABT125 v.1	19960305	-	-	-

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Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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[2] The term 'short data sheet' is explained in section "Definitions".

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Quad buffer; 3-state

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